IN THE UNITED STATES PATENT AND TRADEMARK OFFICE OFFICE OF STATEMENT

SERIAL NO.:

FILED:

April 27, 2001

TITLE:

"INTERFACE ΑN ELECTROPHYSIOLOGY UNIT

MEASUREMENT SYSTEM"

Assistant Commissioner for Patents,

Washington, D.C. 20231

SIR:

In accordance with the provisions of 37 C.F.R. § 1.56, Applicant requests that citation and examination of the following documents be made during the course of examination of the above-referenced application for United States Letters Patent.

> United States Patent No. 5,821,405 AA

> AB United States Patent No. 4,695,955

> AC United States Patent No. 3,805,116

EXPLANATION OF RELEVANCE

The above references were cited in a Search Report rendered by the Swedish Patent Office during examination proceedings for the Swesish application corresponding to the present United States application. A copy of the Swedish Search Report is submitted herewith. Each of these references was cited in Category "A" as general technological background information.

Copies of each of the above references together with Form 1449 are submitted herewith.

As of the date of mailing of this Information Disclosure Statement, a first Office Action on the merits has not been received in connection with this application, and therefore, this Information Disclosure Statement is in compliance with 37 C.F.R. §1.97(b)(3), and no fee is necessary.

All claims of the application are submitted to be patentable over the teachings of the above references, taken singly or in combination. Early consideration of the application is therefore respectfully requested.

Submitted by,

SCHIFF, HARDIN & WAITE

(Reg. 28,982)

CUSTOMER NO. 26574

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CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231 on October 12, 2001.

Steven H. Noll